

A Data Acquisition System using the 10 GSa/s PSEC4 Waveform Digitizing ASIC



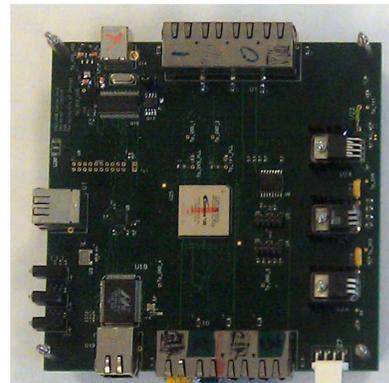
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Abstract

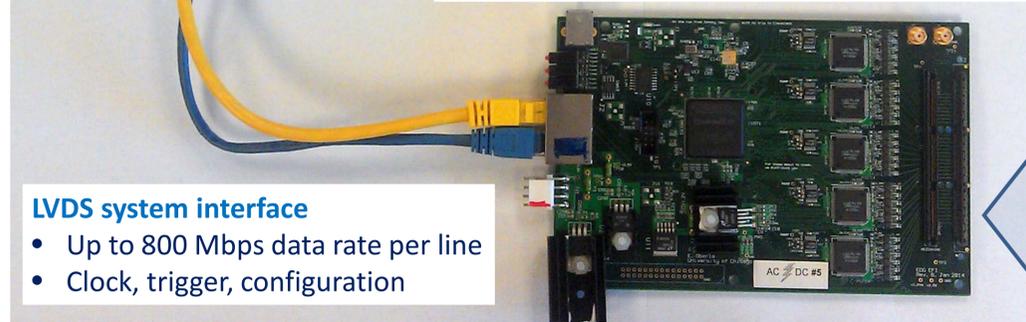
A data acquisition (DAQ) system using the 10 - 15 Gigasample/second (GSa/s) PSEC4 waveform recording Application Specific Integrated Circuit (ASIC) has been developed as part of the Large Area Picosecond Photo-Detector Collaboration (LAPPD). The PSEC4 chip, a 6-channel 0.13 μm CMOS waveform digitizer, was designed as a first generation readout ASIC for these large-area microchannel plate (MCP) photosensors. The full PSEC4 DAQ system architecture incorporates two levels of hardware, FPGA-embedded system control, and data processing. At the front-end is a 30 channel unit that holds five PSEC4 ASICs and a control FPGA that plugs directly into one terminal of the LAPPD MCP anode. The analog bandwidth of the signal input is 1.5 GHz. In order to record waveforms at both ends of the LAPPD anode, two of these cards are required to fully instrument an LAPPD MCP. The back-end card houses the system control FPGA, distributes the system clock, and manages up to four front-end units by means of eight 800 Mbps LVDS lines. This back-end card communicates to a PC using USB 2.0 or gigabit Ethernet.

System Hardware

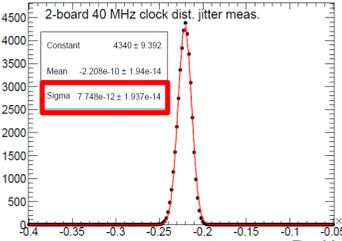
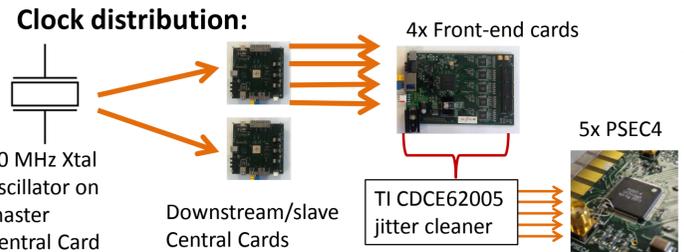


- Central Card**
- Controls 4 front-end boards
 - USB 2.0 or gigabit Ethernet PC connection
 - Daisy chain or tree configurations to extend system channel count
 - Clock fan-out

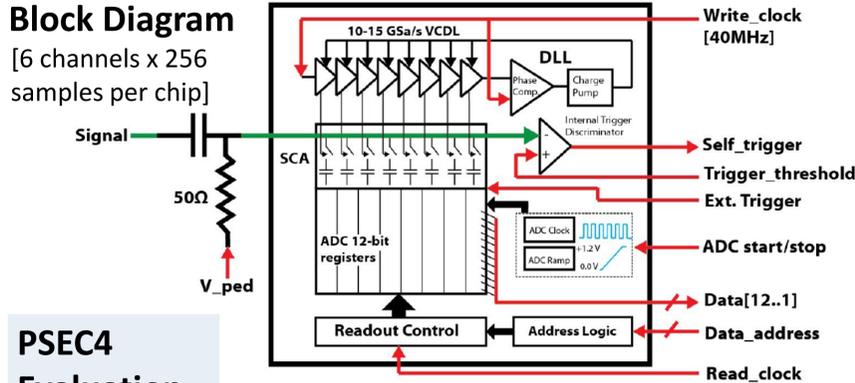
- Front-end PSEC4 Card ("AC/DC Card")**
- 30 channels PSEC4 waveform recording
 - At 10GS/s, captures a 25 ns snapshot per waveform
 - USB 2.0 standalone readout or 8x LVDS lines communication to Central Card



- LVDS system interface**
- Up to 800 Mbps data rate per line
 - Clock, trigger, configuration



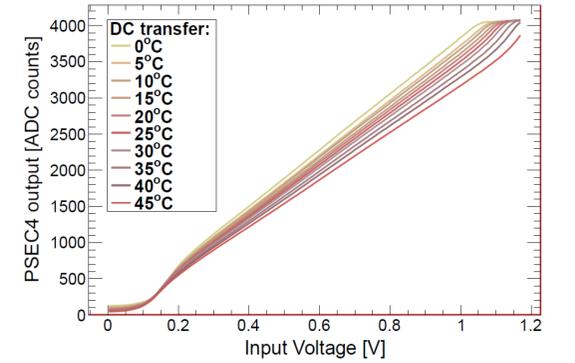
PSEC4 front-end waveform digitizer



PSEC4 Evaluation Card

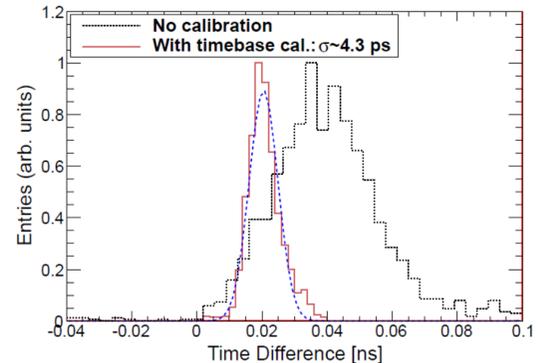


- Signal dynamic range**
- Un-calibrated integral non-linearity 0.15% over 0.75V
 - Full 1V signal voltage range after calibration [out of 1.2V core voltage of 0.13 μm CMOS]

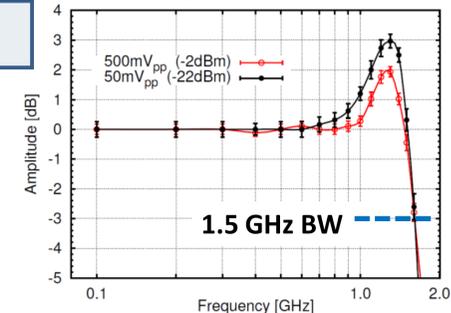


Intra-chip timing

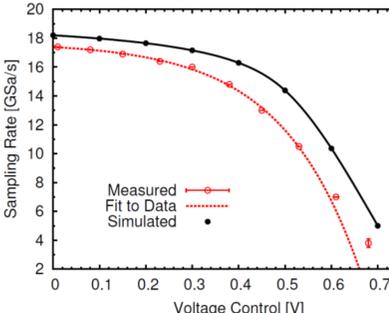
- Measure 2-channel timing before and after time-base calibration
- Record and fit 2 ns FWHM Gaussian pulses and extract time difference
- Timing at the ~few ps level is achieved



Analog Bandwidth



Sampling Rate

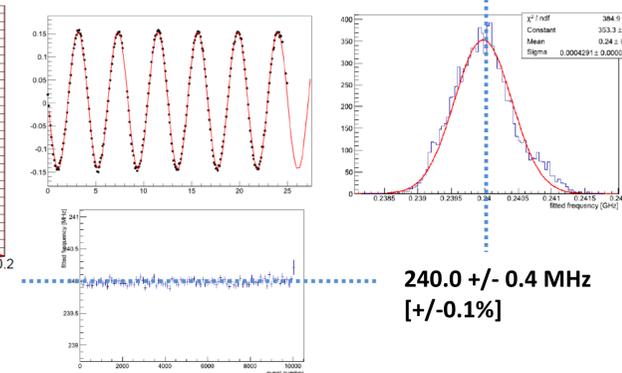
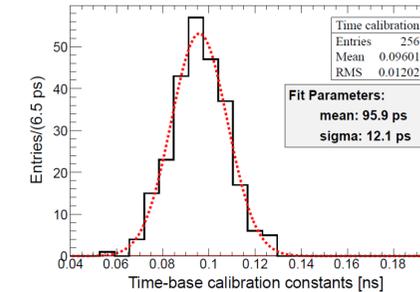
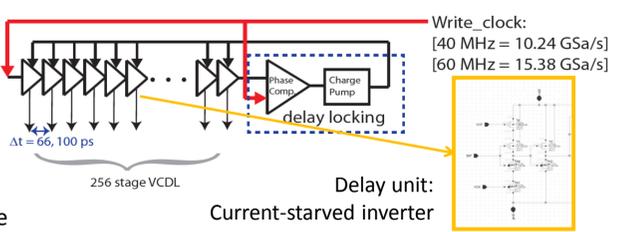


- 1.5 GHz analog bandwidth and 10-15 GSa/s sampling on all channels
- Bandwidth limitation is the RC pole, where C is input parasitic capacitance

Time-base calibration

- Up-convert low frequency (~10's MHz) clock to multi-GHz using tapped voltage-controlled delay line (VCDL)
- Individual delay steps not uniform due to process variations
- Use a 'brute-force' zero-crossing sine wave calibration method, where:

$$\langle \Delta t \rangle = T_{\text{input}} \cdot \langle N_{\text{zero}} \rangle / (2 \cdot N_{\text{events}})$$

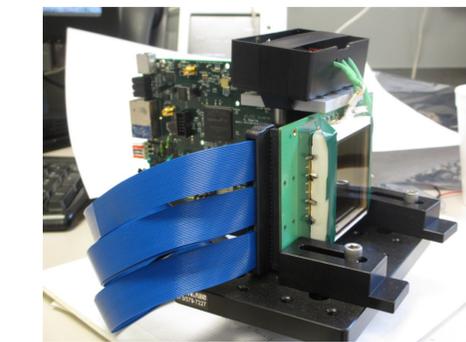


- Use 240 MHz calibration sine
- Measure 13% spread in Δt
- Calibrations required for each channel

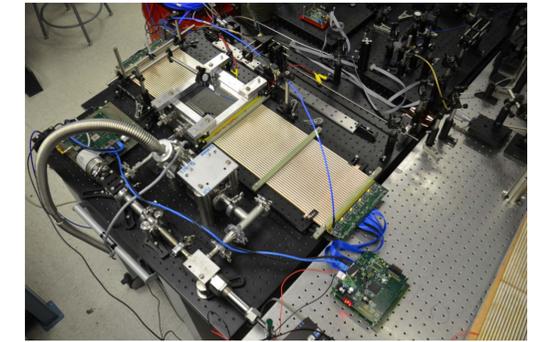
AC/DC front-end board has high bandwidth RF switch on each channel for in-situ electronics timing calibration

Photo-detector Integration

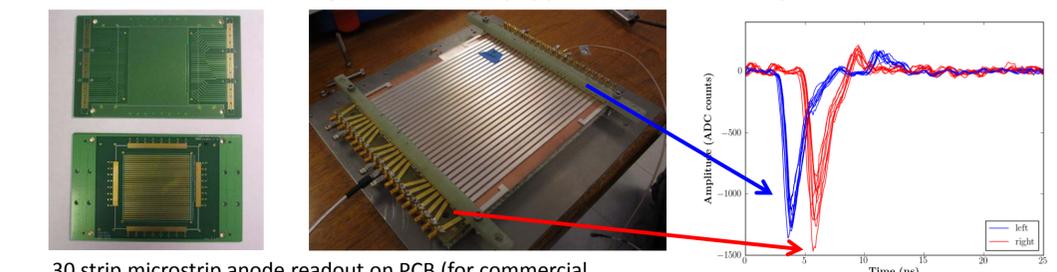
2x2 sq. in Planacon MCP



8x8 sq. in LAPPD MCP



Both MCP detector configurations are equipped with a microstrip anode readout:



30 strip microstrip anode readout on PCB (for commercial Planacons) and silkscreened silver on glass for LAPPDs

References:

A 15 GSa/s, 1.5 GHz Waveform Digitizing ASIC, NIM A732, p452, Jan. 2014.
A test-facility for large-area microchannel plate detector assemblies using a pulsed sub-picosecond laser, RSI, Volume 84, Issue 6.
psec.uchicago.edu